

Report No. MCR-22-0751

Date: Dec./1/2022

RENESAS SEMICONDUCTOR RELIABILITY REPORT

SERIES : RL78/F13

DEVICE : R5F10BGxCyFB/R5F10BGxCyXXXFB

(x=C/D/E/F/G,y=L/K)

APPLICATION: Automobile

Quality Assurance Div.
Renesas Electronics Corporation

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$Q100\ Qualification\ Test\ Results\ for\ R5F10BGxCyFB/R5F10BGxCyXXXFB (x=C/D/E/F/G,y=L/K)$

[Note: Basically qualification tests were performed using a representative product with the same wafer process and the same package structure.]

Test	#	Reference	Test Condition	Lots	S.S.	Total	Results	Comments:	
		Title enec						(Fail of Total)	(N/A =Not Applicable)
1			TEST GRO	OUP A – ACCELERAT	ED ENVIR	ONMENT	STRESS TE	ESTS	
PC	A1	JESD22 A113 J-STD-020	Preconditioning: (Test @ Rm) SMD only; Moisture Preconditioning for THB/HAST, AC/UHST, TC, &PTC Peak Reflow Temp=260°C			Min.MSL=3			-
THB or HAST	A2	JESD22 A101	Temperature Humidity Bias: (Test @ Rm/Ho Ta=85°C, RH=85%, 1000hrs	3	77	231	0 of 231	-	
AC or UHST or TH	A3	JESD22 A118	Unbiased Highly Accelerated Stree Test: (Te 110°C, 85% RH, 264h	3	77	231	0 of 231	-	
TC	A4	JESD22 A104	Temperature Cycle: (Test @ Hot) Ta=-65°C to 150°C, 500cyc	3	77	231	0 of 231 0 Fails after TC (WBP)	-	
PTC	A5	JESD22 A105	Power Temperature Cycle: (Test @ Rm/Hot)	-	-	-	-	N/A	
HTSL	A6	JESD22 A103	High Temperature Storage Life: (Test @ Rm Ta=150°C, 1000hrs	1	45	45	0 of 45	-	
			TEST GRO	OUP B – ACCELERAT	ED LIFET	IME SIMU	LATION TI	ESTS	
HTOL	B1	JESD22 A108	High Temp Operating Life: (Test @ Rm/Col Ta=125°C, 1000hrs	d/Hot)	3	77	231	0 of 231	-
ELFR	В2	AEC-Q100-008	Early Life Failure Rate: (Test @ Rm/Hot) Ta=125°C, 48hrs	3	800	2400	0 of 2400	-	
EDR	В3	AEC-Q100-005	For HTOL NVM Endurance & Data Retention Test:		3	77	231	0 of 231	-
		11DC-Q100-00J	(Test @ Rm/Hot)	For HTSL	1	45	45	0 of 45	-

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Test	#	Reference	Test Conditions		S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)
			TEST GROUP C - PACKAG	E ASSEMB	LY INTEG	RITY TEST	'S	
WBS	C1	AEC-Q100-001 AEC-Q003	Wire Bond Shear Test: (Cpk > 1.67)	30 bonds	5 parts Min.	30 bonds	0 of 30bonds	Cpk>1.67
WBP	C2	Mil-STD-883 Method 2011 AEC-Q003	Wire Bond Pull: (Cpk > 1.67); Each bonder used	30 bonds	5 parts Min.	30 bonds	0 of 30bonds	Cpk>1.67
SD	СЗ	JESD22 B102 JSTD-002D	Solderability: (>95% coverage) 8 hr steam aging prior to testing	1	15	15	0 of 15	-
PD	C4	JESD22 B100, JESD22 B108 AEC-Q003	Physical Dimensions: (Cpk > 1.67)	3	10	30	0 of 30	Cpk>1.67
SBS	C5	AEC-Q100-010 AEC-Q003	Solder Ball Shear: (Cpk > 1.67); 5 balls from min. of 10 devices	-	-	-	-	N/A
LI	C6	JESD22 B105	Lead Integrity: (No lead cracking or breaking); Through-hole only; 10 leads from each of 5 devices	-	-	-	-	N/A
1			TEST GROUP D – DIE FAB	RICATION	RELIABII	ITY TESTS	S	
EM	D1	JESD61	Electromigration:	-	-	-	Pass	Confirmed by process TEG
TDDB	D2	JESD35	Time Dependant Dielectric Breakdown:	-	-	-	Pass	Confirmed by process TEG
HCI	D3	JESD60 & 28	Hot Carrier Injection:	-	-	-	Pass	Confirmed by process TEG
NBTI	D4	JESD90	Negative Bias Temperature Instability:	-	-	-	Pass	Confirmed by process TEG
SM	D5	JESD61,87 & 202	Stress Migration:	-	-	-	Pass	Confirmed by process TEG

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Test	#	Reference	Test Conditions	Lots	S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)
			TEST GROUP E- ELE	CTRICAL	VERIFICA	TION		
TEST	E1	User/Supplier Specification	Pre and Post Stress Electrical Test:	All	All	All	0 of All	-
НВМ	E2	AEC-Q100-002	Electrostatic Discharge, Human Body Model: (Test @ Rm/Hot); (2KV HBM / Class 2 or better)	1	3	3	0 of 3 ESD Level= HBM:2	HBM>2KV
CDM	E3	AEC-Q100-011	Electrostatic Discharge, Charged Device Model: (Test @ Rm/Hot); (750V corner leads, 500V all other leads / Class C4B or better)	1	3	3	0 of 3 ESD Level= CDM:C4B	Corner leads: 750V Pass All other leads:500V Pass
LU	E4	AEC-Q100-004	Latch-Up: (Test @ Rm/Hot)	1	6	6	0 of 6	-
ED	E5	AEC-Q100-009 AEC-Q003	Electrical Distributions: (Test @ Rm/Hot/Cold) (where applicable, Cpk>1.67)	3	30	90	Cpk>1.67	-
FG	E6	AEC-Q100-007	Fault Grading:	1	-	-	>98%	-
CHAR	E7	AEC-Q003	Characterization: (Test @ Rm/Hot/Cold)	1	-	-	Pass	According to Renesas standard procedure
EMC	E9	SAE J1752/3	Electromagnetic Compatibility (Radiated Emissions)	1	1	1	0 of 1	-
SC	E10	AEC Q100-012	Short Circuit Characterization	-	-	-	-	N/A
SER	E11	JESD89-1 JESD89-2 JESD89-3	Soft Error Rate	1	3	3	Pass	-
LF	E12	AEC-Q005	Lead (Pb) Free: (see AEC-Q005)	-	-	-	Pass	Solderability: See SD (C3) result. Solder heat resistance: N/A (Wave Solder is Not recommended.) Whisker: Performed on product TEG with test method based on JESD201.

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Test	#	Reference	Test Conditions Lots S.S. Total Results (Fail of Tot			Results (Fail of Total)	Comments: (N/A =Not Applicable)			
			TEST GROUP F – DE	FECT SCR	EENING T	ESTS				
PAT	F1	AEC-Q001	Process Average Testing: (see AEC-Q001)	All	All	All	Reject units outside PAT limits	Apply to mass production according to Renesas standard procedure		
SBA	F2	AEC-Q002	Statistical Bin/Yield Analysis: (see AEC-Q002)	All	All	All	Reject units outside criteria	Apply to mass production according to Renesas standard procedure		
	TEST GROUP G - CAVITY PACKAGE INTEGRITY TESTS (for Ceramic Package testing only)									
MS	G1	JESD22 B104	Mechanical Shock: (Test @ Rm)	-	-	-	-	N/A		
VFV	G2	JESD22 B103	Variable Frequency Vibration: (Test @ Rm)	-	-	-	-	N/A		
CA	G3	MIL-STD-883 Method 2001	Constant Acceleration: (Test @ Rm)	-	-	-	-	N/A		
GFL	G4	MIL-STD-883 Method 1014	Gross and Fine Leak:	-	-	-	-	N/A		
DROP	G5		Drop Test: (Test @ Rm) MEMS cavity parts only. Drop part on each of 6 axes once from a height of 1.2m onto a concrete surface.	-	-	-	-	N/A		
LT	G6	MIL-STD-883 Method 2004	Lid Torque:	-	-	-	-	N/A		
DS	G7	MIL-STD-883 Method 2019	Die Shear:	-	-	-	-	N/A		
IWV	G8	MIL-STD-883 Method 1018	Internal Water Vapor:	-	-	-	-	N/A		

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Calculation method of standard failure rate

Target: 0.13um CMOS process product (RL78 series Automobile)

Operating reliability is decided by inherent reliability of device and environment condition of use (See below).

Calculation method of standard failure rate (λ)

$$\lambda = \underline{\lambda b} \times \underline{\pi T}$$
 (FIT)
$$(2)$$
 Temperature parameter
$$(1)$$
 Basic failure rate

(1)Basic failure rate(λb)

 $\lambda b: 0.18 \text{ (FIT)}$

(2)Temperature parameter

$$\pi T = \exp \left\{ 11600 \times \text{Ea} \times \left(\frac{1}{273+55} - \frac{1}{273+\text{Ta}} \right) \right\}$$

Ea : Activation energy (eV)
Ta : ambient temperature

πT Simplified chart (Ea=0.7eV)												
Ta(°C)	40	50	55	60	65	70	75	80	85	90	100	110
πТ	0.31	0.68	1	1.45	2.08	2.95	4.15	5.77	7.96	10.88	19.82	34.99

-Confidence level 60% -Standard temperature Ta=55°C

(3)MTTF (Mean Time To Failure)
$$MTTF = \frac{1}{\lambda}$$



Product list Report No. MCR-22-0751

Prout							11 NO. MCK-22-0731
No	Group	Product part number	Package code	No	Group	Product part number	Package code
1	RL78/F13	R5F10BGCCKFB	PLQP0048KF-A	51			
2	RL78/F13	R5F10BGCCKXXXFB	PLQP0048KF-A	52			
3	RL78/F13	R5F10BGCCLFB	PLQP0048KF-A	53			
4	RL78/F13	R5F10BGCCLXXXFB	PLQP0048KF-A	54			
5	RL78/F13	R5F10BGDCKFB	PLQP0048KF-A	55			
6	RL78/F13	R5F10BGDCKXXXFB	PLQP0048KF-A	56			
7	RL78/F13	R5F10BGDCLFB	PLQP0048KF-A	57			
8	RL78/F13	R5F10BGDCLXXXFB	PLQP0048KF-A	58			
9	RL78/F13	R5F10BGECKFB	PLQP0048KF-A	59			
10	RL78/F13	R5F10BGECKXXXFB	PLQP0048KF-A	60			
11	RL78/F13	R5F10BGECLFB	PLQP0048KF-A	61			
12	RL78/F13	R5F10BGECLXXXFB	PLQP0048KF-A	62			
13	RL78/F13	R5F10BGFCKFB	PLQP0048KF-A	63			
14	RL78/F13	R5F10BGFCKXXXFB	PLQP0048KF-A	64			
15	RL78/F13	R5F10BGFCLFB	PLQP0048KF-A	65			
16	RL78/F13	R5F10BGFCLXXXFB	PLQP0048KF-A	66			
17	RL78/F13	R5F10BGGCKFB	PLQP0048KF-A	67			
18	RL78/F13	R5F10BGGCKXXXFB	PLQP0048KF-A	68			
19	RL78/F13	R5F10BGGCLFB	PLQP0048KF-A	69			
20	RL78/F13	R5F10BGGCLXXXFB	PLQP0048KF-A	70			
21	-, -			71			
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36				86	1		
37				87	1		
38				88			
39				89			
40				90	+		
41				91	+		
42				92			
42 43	1	+		93			
43 44				94			
44 45				95			
		+		96	1		
46 47					1		
47				97			
48				98			
49				99			
50				100			